Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
08439095	MATSUI ET AL.	
Examiner	Art Unit	
Skibinsky, Anna	1631	

SEARCHED				
Class	Subclass	Date	Examine	

SEARCH NOTES				
Search Notes	Date	Examiner		
Sequence search for SEQ ID NOs: 1 and 2	5/15/2006	STIK		

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